Practical exercise on film thickness quantification with XPS

SURFACE ANALYSIS

MSE-351

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Experimental conditions of the sample

- Aluminum oxide formed on an Aluminum substrate:
  - Formation of an oxide film
  - Angle resolved XPS analysis of the aluminum oxide film on the aluminum substrate

Please, do the following

- Identify the oxide and metallic peaks.
- Determine the film thickness of the aluminum oxide film out of the spectrum shown below.

Angle resolved XPS analysis